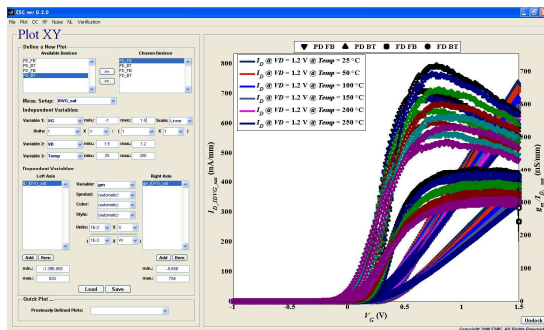




Electronic Semiconductor Characterization Tool (ESC):

Sopartec, the technology transfer company of the Université catholique de Louvain (UCL), presents a unique Electronic Semiconductor Characterization tool (ESC).



Technology Keywords:

- Direct device parameter extraction
- Multiple extraction techniques into a single tool
- Handling of DC, AC, RF, non-linear and noise data
- CMOS (bulk/SOI), Bi-CMOS

Technology Market: Semiconductor Industry

The ESC software gathers in a unique and flexible tool a large variety of semiconductor device characterization techniques, thereby addressing the needs of Research Centers (process development), Semiconductor foundries (quality control) as well as Design houses (technology assessment).

UCL software: Key benefits

- **Broad input data formats:** our software handles all major input data file formats,
- **Multiple extraction techniques:** a wide variety of direct extraction techniques (i.e., without the need for optimization) are embedded in a single environment and cover various modes of

operation including DC, AC, RF, non-linear, noise, etc.

- **Flexible tool:** the software provides a straightforward procedure to add new devices and/or new extraction methodologies,
- **Equivalent circuit verification:** each extracted parameter can be verified using a specific tuning variable,
- **User friendly presentation:** large amounts of data can be manipulated, either for data consistency evaluation, device performance comparison or comparison between distinct extraction techniques,
- **Time saving process:** up to 10 times faster than any case by case or individual effort to fully characterize a semiconductor device.

Sopartec is willing to provide different license schemes of the Electronic Semiconductor Characterization tool (ESC) for interested parties.

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